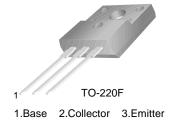


KSC5367F

High Voltage and High Reliability

- High speed Switching
- Wide Safe Operating Area
- High Collector-Base Voltage



NPN Triple Diffused Planar Silicon Transistor

Absolute Maximum Ratings $T_C=25^{\circ}C$ unless otherwise noted

Symbol	Parameter	Value	Units
V _{CBO}	Collector-Base Voltage	1600	V
V _{CEO}	Collector-Emitter Voltage	800	V
V _{EBO}	Emitter-Base Voltage	12	V
I _C	Collector Current (DC)	3	А
I _{CP}	*Collector Curren (Pulse)	6	А
I _B	Base Current (DC)	2	Α
I _{BP}	*Base Current (Pulse)	4	А
P _C	Power Dissipation(T _C =25°C)	40	W
T _J	Junction Temperature	150	°C
T _{STG}	Storage Temperature	- 65 ~ 150	°C

^{*} Pulse Test: Pulse Width=5ms, Duty Cycle≤10%

Thermal Characteristics $\rm T_{C}\text{=}25^{\circ}C$ unless otherwise noted

Symbol	Characteristics		Rating	Unit
$R_{\theta jc}$	Thermal Resistance	Junction to Case	3.1	°C/W
$R_{\theta ja}$		Junction to Ambient	62.5	

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$\textbf{Electrical Characteristics} \ \, \textbf{T}_{\text{C}} = 25 \, ^{\circ} \text{C unless otherwise noted}$

Symbol	Parameter	Test Condition	Min.	Тур.	Max.	Units
BV _{CBO}	Collector-Base Breakdown Voltage	$I_C = 0.5 \text{mA}, I_E = 0$	1600	-	-	V
BV _{CEO}	Collector-Emitter Breakdown Voltage	$I_C = 5mA, I_B = 0$	800	-	-	V
BV _{EBO}	Emitter-Base Breakdown Voltage	$I_C = 0.5 \text{mA}, I_C = 0$	12	-	-	V
I _{CBO}	Collector Cut-off Current	$V_{CB} = 1,600V, I_{E} = 0$	-	-	20	μΑ
I _{EBO}	Emitter Cut-off Current	$V_{EB} = 12V, I_{C} = 0$	-	-	20	μΑ
h _{FE1}	DC Current Gain	$V_{CE} = 3V, I_{C} = 0.4A$	12	-	35	
h _{FE2}		$V_{CE} = 10V, I_{C} = 5mA$	8	-	-	
V _{CE} (sat)	Collector-Emitter Saturation Voltage	$I_C = 250 \text{mA}, I_B = 25 \text{mA}$	-	-	2.5	V
		$I_C = 500 \text{mA}, I_B = 50 \text{mA}$	-	-	4.0	V
		$I_C = 1A, I_B = 0.2A$	-	-	2.5	V
V _{BE} (sat)	Base-Emitter Saturation Voltage	$I_C = 500 \text{mA}, I_B = 50 \text{mA}$	-	-	1.5	V
C _{ob}	Output Capacitance	$V_{CB} = 10V, I_{E} = 0, f = 1MHz$	-	40	-	pF
t _{ON}	Turn ON Time	$V_{CC} = 125V, I_{C} = 0.5A$	-	-	0.5	μs
t _{STG}	Storage Time	$I_{B1} = 42\text{mA}, \ I_{B2} = -333\text{mA}$ $R_L = 250\Omega$		-	2.2	μs
t _F	Falling Time		-	-	0.5	μs
t _{ON}	Turn ON Time	$V_{CC} = 250V, I_{C} = 1A$	-	-	0.5	μs
t _{STG}	Storage Time	$I_{B1} = 0.2A, I_{B2} = -0.4A$ $R_L = 250\Omega$	-	-	4.0	μs
t _F	Falling Time		-	-	0.5	μs

Typical Characteristics

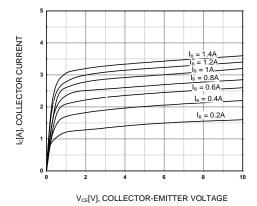


Figure 1. Static Characteristic

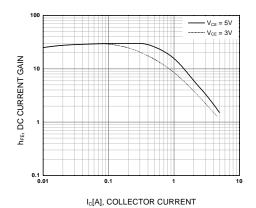


Figure 2. DC current Gain

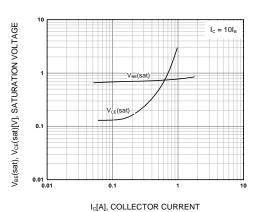


Figure 3. Base-Emitter Saturation Voltage Collector-Emitter Saturation Voltage

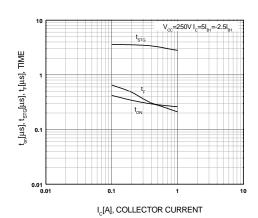


Figure 4. Switching Time

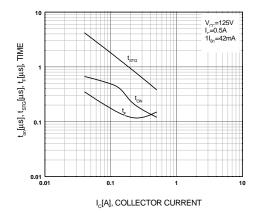


Figure 5. Switching Time

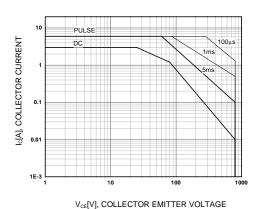


Figure 6. Safe Operating Area

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Typical Characteristics (Continued)

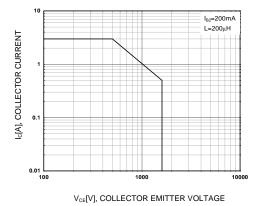


Figure 7. Reverse Bias Safe Operating Area

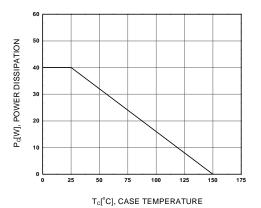
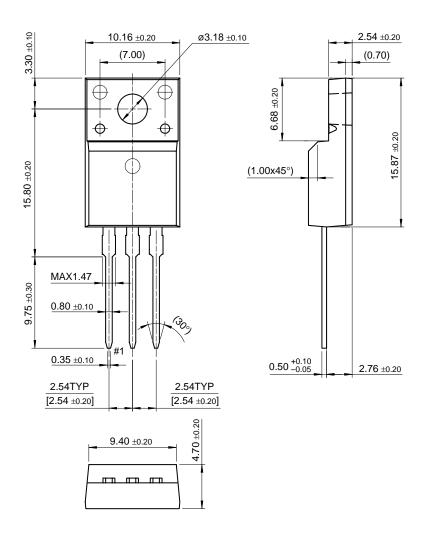


Figure 8. Power Derating

Package Demensions

TO-220F



Dimensions in Millimeters

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